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Mega trends & advanced packaging are reshaping the ways of testing systems

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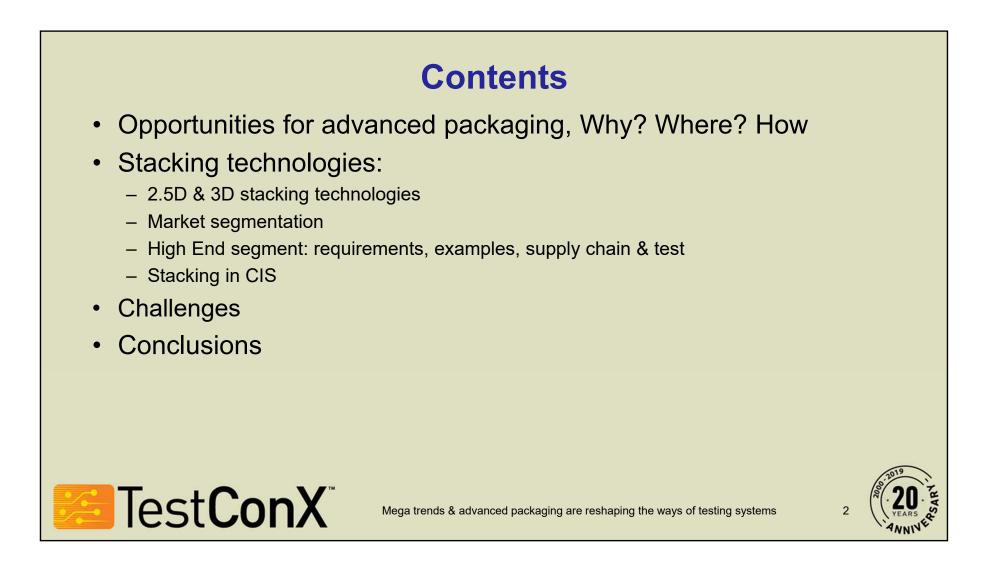


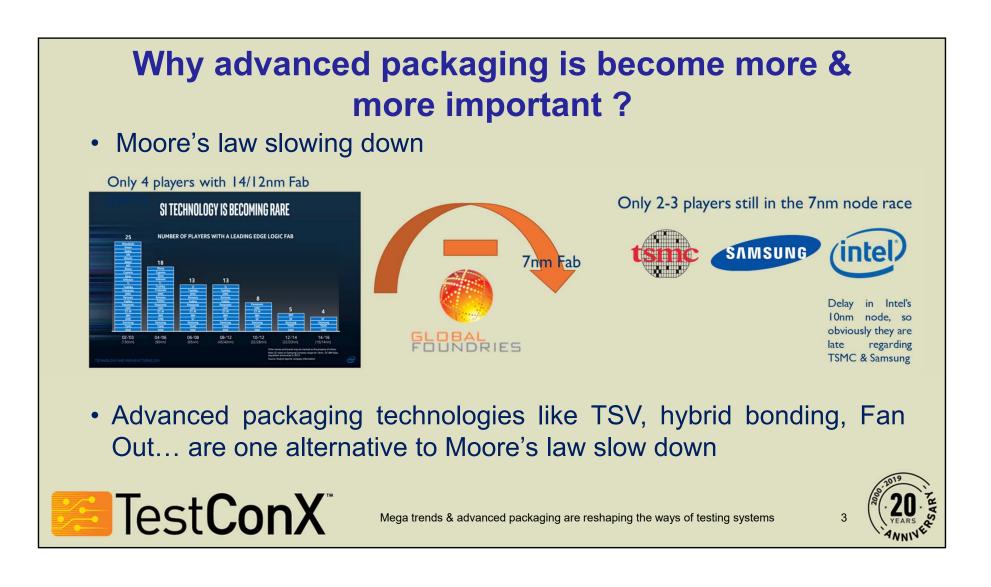


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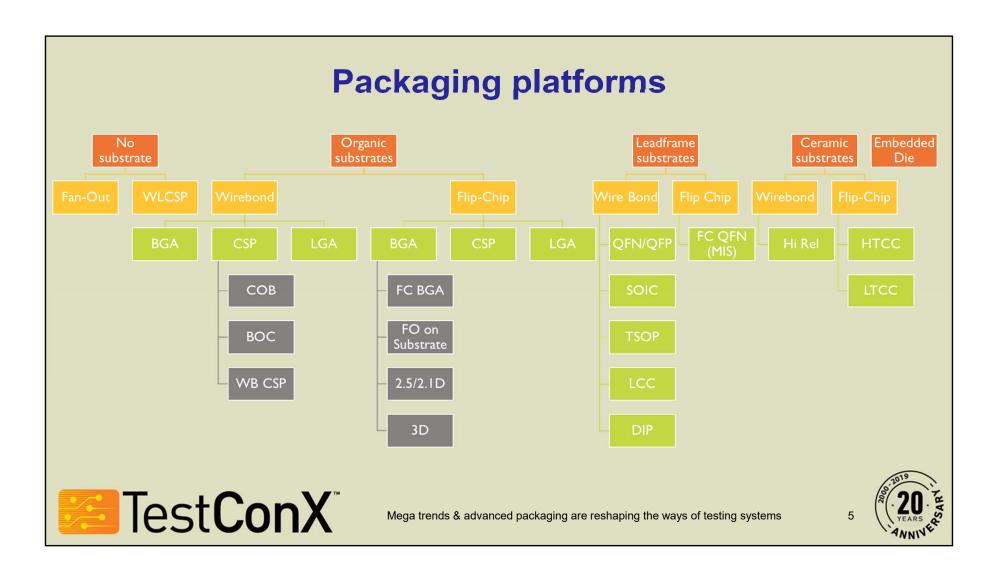
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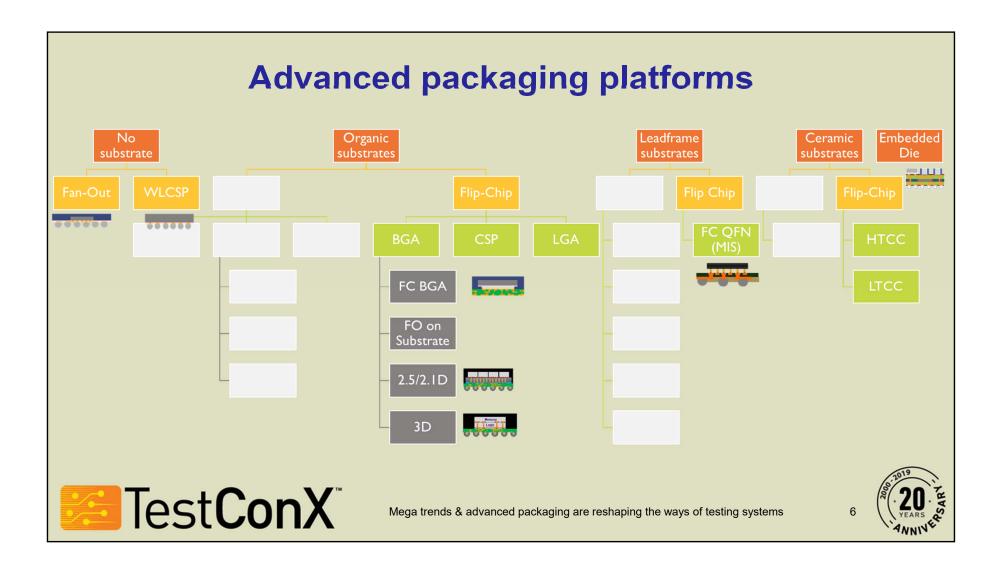


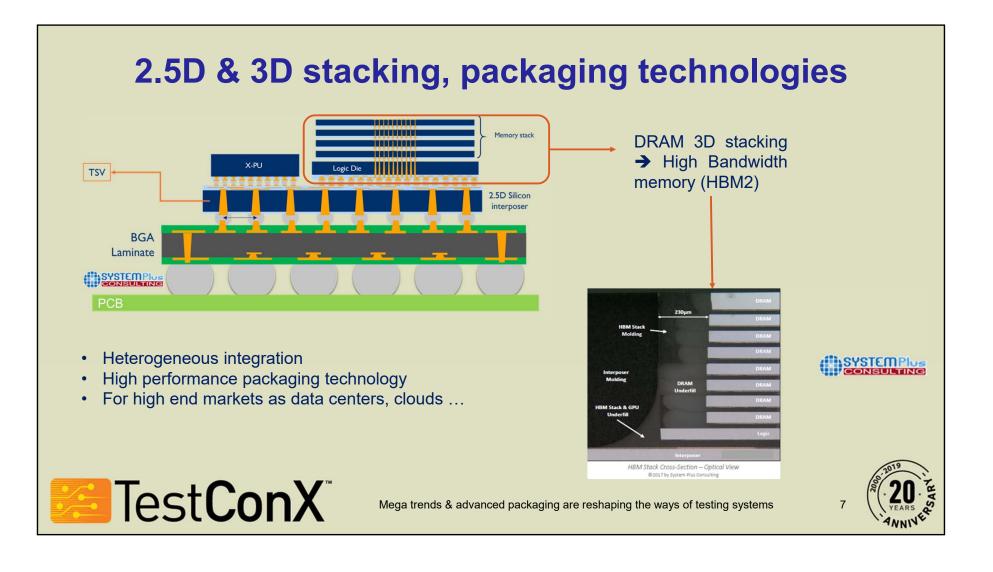






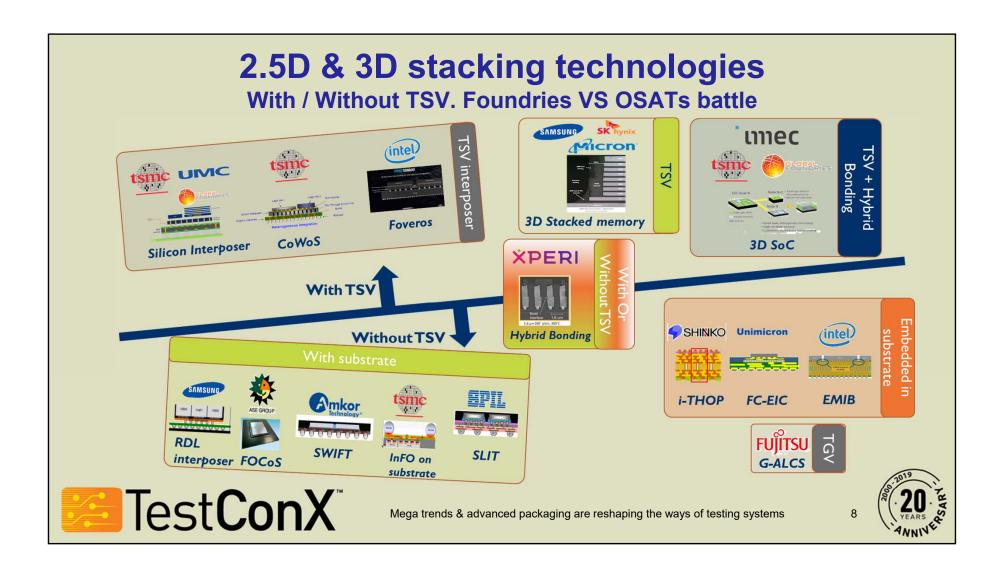
By The Numbers - Market Session



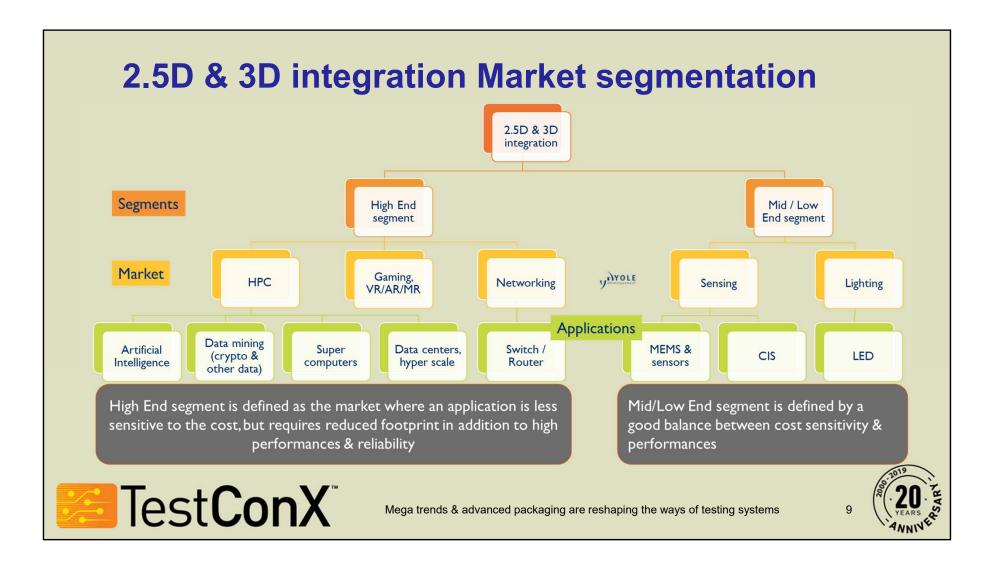


Session 5A Presentation 2

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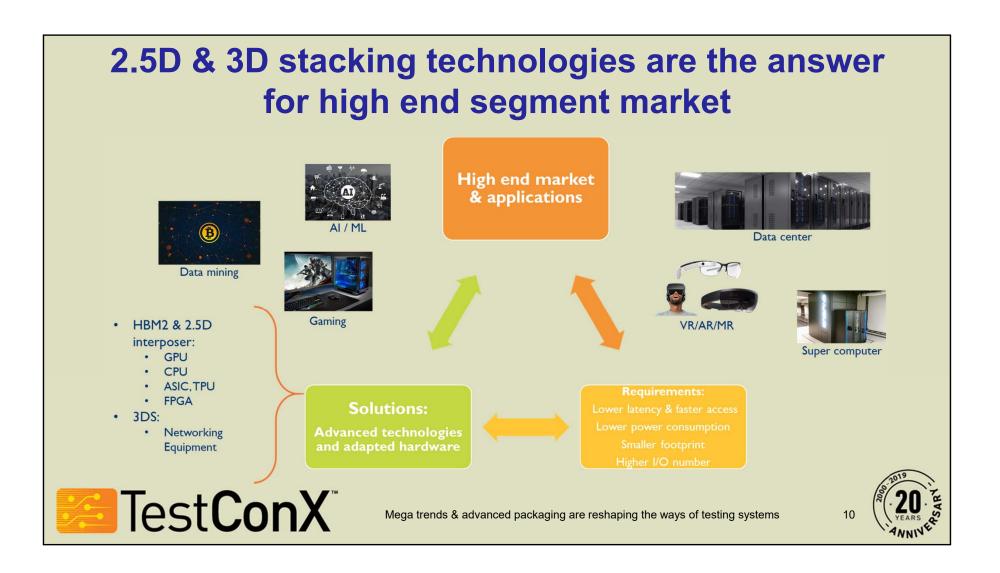


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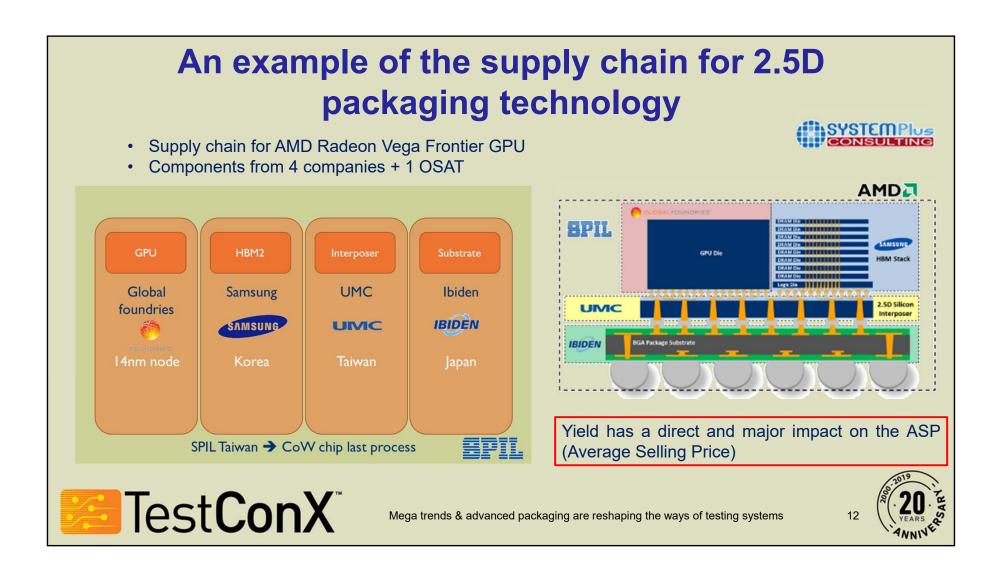
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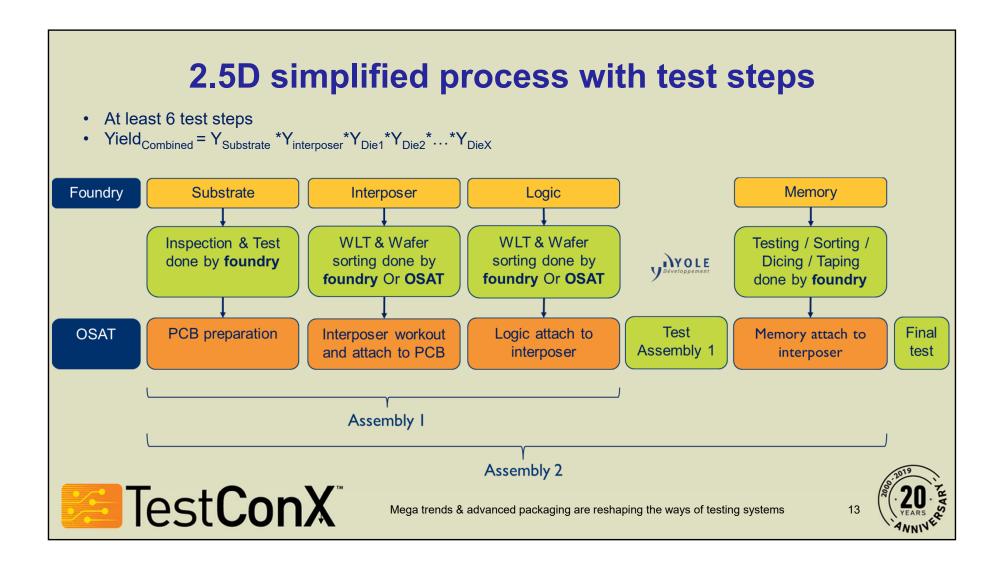


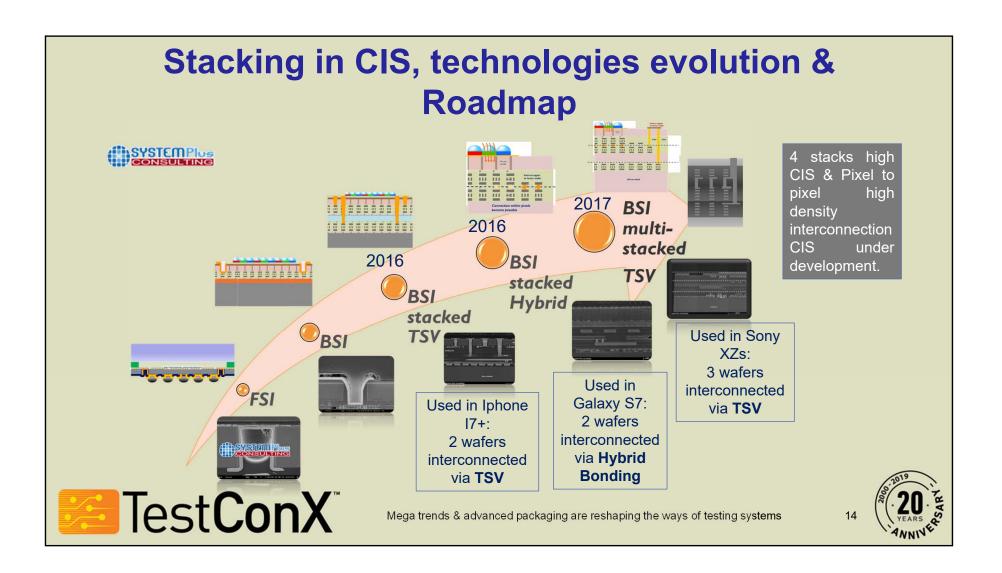
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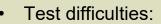




By The Numbers - Market Session

New challenges induced by stacking technologies

- Thin wafer handling:
 - 100 μ m wafer thickness to handle \rightarrow White paper thickness
- Bow management:
 - Alignment difficulties
 - Probe testing difficulties
 - Cracks induced by vacuum on tester/prober
 - Cracks induced by probing with Bow



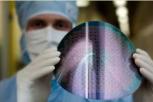
- Specific test structures need to be implemented (E-fuses in Si interposer for example)
- Difficulties to test small Cu micro bumps → Larger test pads & additional test paths needed (design rule)
- Burn In test:
 - Complexity to identify the origin of a failure occurring at the system level with different devices & layers
 - Reliability is crucial for some markets as automotive

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Source: Research Gate





Source: Fraunhofer IZM

TSV & Hybrid bonding, packaging revenues

- Stacking technologies based on TSV or Hybrid bonding considered
- **\$5.7B** packaging revenues for stacking technologies in **2023**

TSV & Hybrid bonding packaging revenues (M\$) 6 000 5 000 4 000 3 000 2 000 1 000 0 2017 2018 2019 2020 2021 2022 2023 TSV & HB 1 334 1 756 2 3 5 4 3 266 4 104 4 887 5 702



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Conclusions

- Stacking technologies = one solution to Moore's law slow down
- Stacking technologies are widely used in high end markets but are also present in Mid/low end applications
- \$5.7B stacking technologies, packaging revenues in 2023
- TSV is the dominant technology but is being challenged
- Yield is important when talking about ASP
- Test is a crucial, complex & challenging step of the process
- Reliability test is important for advanced packaged systems, especially when related to stringent markets as automotive



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